

Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 1 of 10

SFI ELECTRONICS TECHNOLOGY INC.

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

送樣廠商(Sample Submitted By) : 立昌先進科技股份有限公司 (SFI ELECTRONICS TECHNOLOGY INC.)

樣品名稱(Sample Description) : TRANSIENT VOLTAGE SUPPRESSORS(T. V. S)SMD MULTILAYER

樣品型號(Style/Item No.) : FULL SIZE(ML-A/C SERIES, ESD SERIES, CH SERIES, HIGH CAP SERIES,

LOW CAP SERIES, ESD+EMI SERIES, ARRAY SERIES, SHA SERIES, SHN SERIES,

SHC SERIES , SHV SERIES , SEM SERIES , SEA SERIES , SEH SERIES ,

STS SERIES, MH SERIES, SAD SERIES)

收件日期(Sample Receiving Date) : 2015/06/25

測試期間(Testing Period) : 2015/06/25 TO 2015/07/07

测試結果(Test Results) : 請見下一頁 (Please refer to next pages).



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at http://www.sgs.com/en/Terms-and-Conditions.aspx and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at http://www.sgs.com/en/Terms-and-Conditions/Terms-e-Document.aspx. Attention of advant to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document document only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document document on the company and the company and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document and this document document and this document on the company and the company and the company and the company and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document and this document document and this document and t



Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 2 of 10

SFI ELECTRONICS TECHNOLOGY INC.

測試結果(Test Results)

測試部位(PART NAME)No.1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值	結果(Result)	
(1000 100mb)	(01110)	(mo triod)	(MDL)	No. 1	
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應 耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n. d.	
鉛 / Lead (Pb)	mg/kg	參考IEC 62321-5: 2013方法, 以感應 耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	8. 61	
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法, 以感應 耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n. d.	
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	参考IEC 62321: 2008方法,以UV-VIS 檢測. / With reference to IEC 62321: 2008 and performed by UV- VIS.	2	n. d.	
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg	參考IEC 62321-8 (111/321/CD),以氣相層析儀/質譜儀檢測之. / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.	
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg	參考IEC 62321-8 (111/321/CD),以氣相層析儀/質譜儀檢測之. / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.	



Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 3 of 10

SFI ELECTRONICS TECHNOLOGY INC.

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
鄰苯二甲酸二異丁酯 / DIBP (Di-isobutyl phthalate) (CAS No.: 84-69-5)	mg/kg	参考IEC 62321-8 (111/321/CD),以氣相層析儀/質譜儀檢測之. / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二 (2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg	参考IEC 62321-8 (111/321/CD),以氣相層析儀/質譜儀檢測之. / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n. d.
多溴聯苯總和 / Sum of PBBs	mg/kg		-	n. d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n. d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n. d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n. d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n. d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n. d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n. d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n. d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n. d.
九溴聯苯 / Nonabromobiphenyl	mg/kg	參考IEC 62321-6: 2015方法, 以氣相	5	n. d.
十溴聯苯 / Decabromobiphenyl	mg/kg	層析/質譜儀檢測. / With reference	5	n. d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	to IEC 62321-6: 2015 and performed	-	n. d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg	by GC/MS.	5	n. d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg]	5	n. d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg]	5	n. d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg]	5	n. d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n. d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg]	5	n. d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg]	5	n. d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg]	5	n. d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg]	5	n. d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg]	5	n. d.



Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 4 of 10

SFI ELECTRONICS TECHNOLOGY INC.

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值	結果 (Result)
(lost loms)	(OIII t)	(mo triod)	(MDL)	No. 1
鹵素 / Halogen				
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg		50	n. d.
鹵素 (氣) / Halogen-Chlorine (C1) (CAS No.: 22537-15-1)	mg/kg	參考BS EN 14582:2007,以離子層析儀 分析./ With reference to BS EN	50	n. d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)		14582:2007. Analysis was performed by IC.	50	n. d.
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n. d.

釋出鎳 / Nickel Release Test

测試方法(Method):

参考EN 1811:2011+AC:2012方法處理, 以感應耦合電漿原子發射光譜儀分析. / With reference to EN 1811:2011+AC:2012. Analysis was performed by ICP-AES.

樣品 (Sample)	樣品表面積 (Sample Area) (cm²)	測試溶液體積 (Volume of Test Solution) (ml)	釋出鎮 (Nickel Release) (µg/cm²/week)		
No. 1	7. 1	10	<0. 1 <0. 1 <0. 1		



Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 5 of 10

SFI ELECTRONICS TECHNOLOGY INC.

備註(Note):

- 1. mg/kg = ppm; 0. 1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. "-" = Not Regulated (無規格值)
- 5. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

6. μg/cm²/week = microgram per square centimeter per week

٠.	487 cm 7 week milet og tam per oquare centrimeter per week						
7.	1% railer rail	釋出鎳 / Nickel Release (μg/cm²/week)					
	樣品類別 (Type of sample)	通過(PASS)	不確定 (No clear decision)*	失敗(FAIL)			
	釋出鎳成品含量限值為0.5μg/cm²/week (一般類樣品)/ Article with Nickel release limit of 0.5μg/cm²/week (Non-body piercing)	≤ 0.28	>0.28 and <0.88	≥ 0.88			
	釋出鎳成品含量限值為0.2μg/cm²/week (穿刺人體類樣品)/ Article with Nickel release limit of 0.2μg/cm²/week (Body piercing)	≤ 0.11	>0.11 and <0.35	≥ 0.35			

^{* =} No clear decision = Inconclusive (不確定)

Method Detection Limit (方法偵測極限值) = 0.1 μg/cm²/week

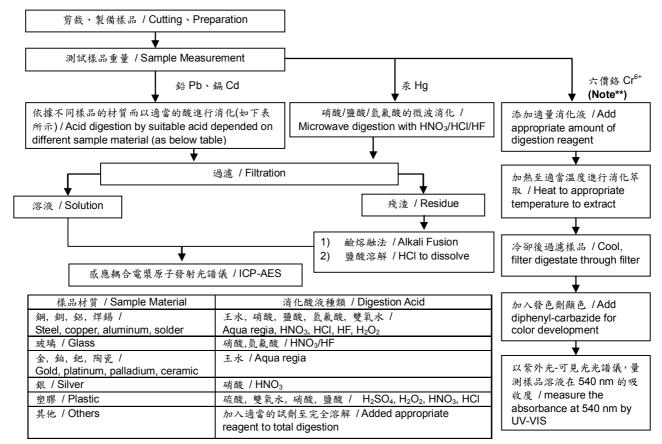


Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 6 of 10

SFI ELECTRONICS TECHNOLOGY INC.

- 1) 根據以下的流程圖之條件,樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) 测試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 测試負責人:張啟興 / Name of the person in charge of measurement: Troy Chang



Note** (For IEC 62321)

- (1) 針對非金屬材料加入鹼性消化液,加熱至 90~95℃萃取. / For non-metallic material, add alkaline digestion reagent and heat to 90~95℃.
- (2) 針對金屬材料加入純水,加熱至沸騰萃取. / For metallic material, add pure water and heat to boiling.



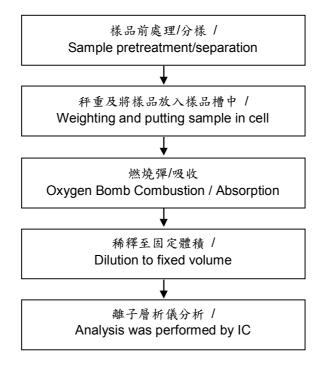
測試報告 Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 7 of 10

SFI ELECTRONICS TECHNOLOGY INC.

鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員:陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人:張啟興 / Name of the person in charge of measurement: Troy Chang





測試報告 Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07

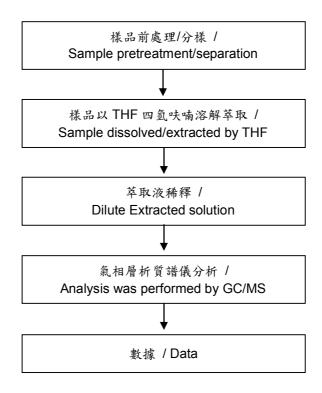
頁數(Page): 8 of 10

SFI ELECTRONICS TECHNOLOGY INC.

可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員:徐毓明 / Name of the person who made measurement: Andy Shu
- 測試負責人:張啟興 / Name of the person in charge of measurement: Troy Chang

【測試方法/Test method: IEC 62321-8】





測試報告 Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 9 of 10

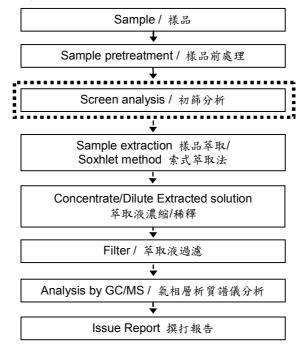
SFI ELECTRONICS TECHNOLOGY INC.

多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong

選擇性篩檢程序 / Optional screen process ••••••

確認程序 / Confirmation process - · - · ▶





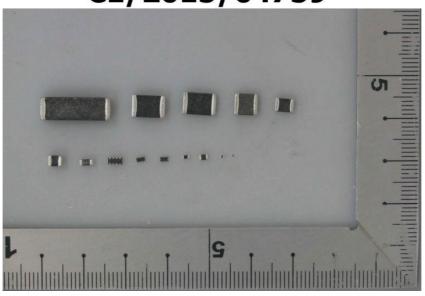
Test Report

號碼(No.): CE/2015/64759 日期(Date): 2015/07/07 頁數(Page): 10 of 10

SFI ELECTRONICS TECHNOLOGY INC.

* 照片中如有箭頭標示,則表示為實際檢測之樣品/部位. * (The tested sample / part is marked by an arrow if it's shown on the photo.)

CE/2015/64759



** 報告結尾 (End of Report) **